QUERY CONTROL FORM			RTIS US	SE ONLY
Application No. 106 55 714	Prepared by	PAP	Tracking Number	05971879
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a. Serial No.	f. Foreign Priority	k. Print Claim(s)	(p) PTO-1449		
b. Applicant(s)	g. Disclaimer	I. Print Fig.	q. PTOL-85b		
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract		
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs		
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other		

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`	SoftSigne Form PTO-1449 U.S. Department of Commerce Patent and Trademark Office			Attorney's Docket No. 005-010	Application No. 10/055,714					
	AUB 2 9 2003	Information Disclosure Statement by Applicant				Applicant SEPETKA et al.				
BITTER	(Use several sheets if necessary) (37 CFR §1,98(b))				Filing Date January 22, 2002		Group Art Unit 3731			
	ANEMARY.			II C Poton	t Documents					
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